Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination		
10/665,611	CHEN ET AL.		
Examiner	Art Unit		
Aung T. Win	2617		

SEARCHED						
Class	Subclass	Date	Examiner			
370	332	5/10/2007	ATW			
370	231-235	5/10/2007	ATW			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

DATE 5/9/2007	EXMR
5/9/2007	ATW
5/10/2007	ATW
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	5/10/2007